

Modeling of PV Module Power Degradation to Evaluate Performance Warranty Risks



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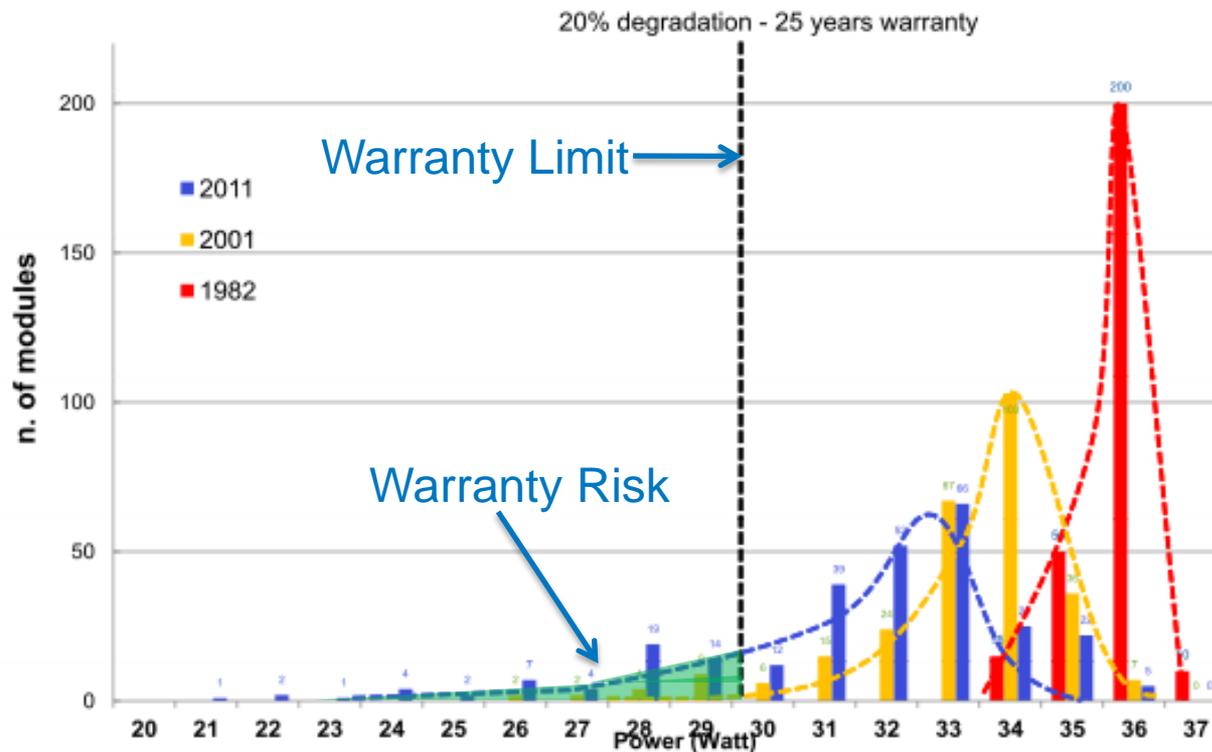
²Yingli Green Energy Americas, Inc.

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Santa Clara, CA. May 1-2, 2013.



Motivation

- Module manufacturers provide performance warranties
- Goal: Quantify associated financial risk
- Illustration: Data from SUPSI – ISAAC PV system built 1982



T. Friesen,
presented at
2nd SOPHIA
Workshop
PV-Module
Reliability”,
May 3-4, 2012,
Lugano.



Model for time evolution of module power distributions is needed!

Outline

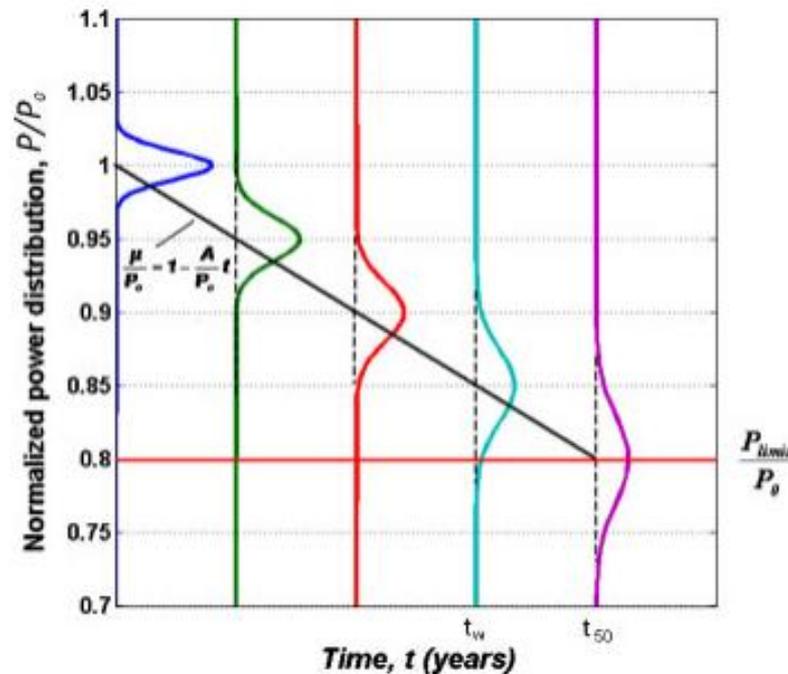
- Motivation
- Context
- Annual Degradation Rate: A Fresh Look
- Systematic Approaches:
 - ✓ Monte Carlo
 - ✓ Convolution
- Application
- Summary and Outlook



Context: Vázquez and Rey-Stolle

- Time evolution of a Gaussian distribution of module powers

$$p(P, t) = \frac{1}{\sqrt{2\pi}(\sigma_0 + Bt)} \exp \left\{ -\frac{1}{2} \left[\frac{P - (P_0 - At)}{\sigma_0 + Bt} \right]^2 \right\}$$



M. Vázquez and
I. Rey-Stolle,
Prog. Photovolt.:
Res. Appl.
16 (2008) p. 419.

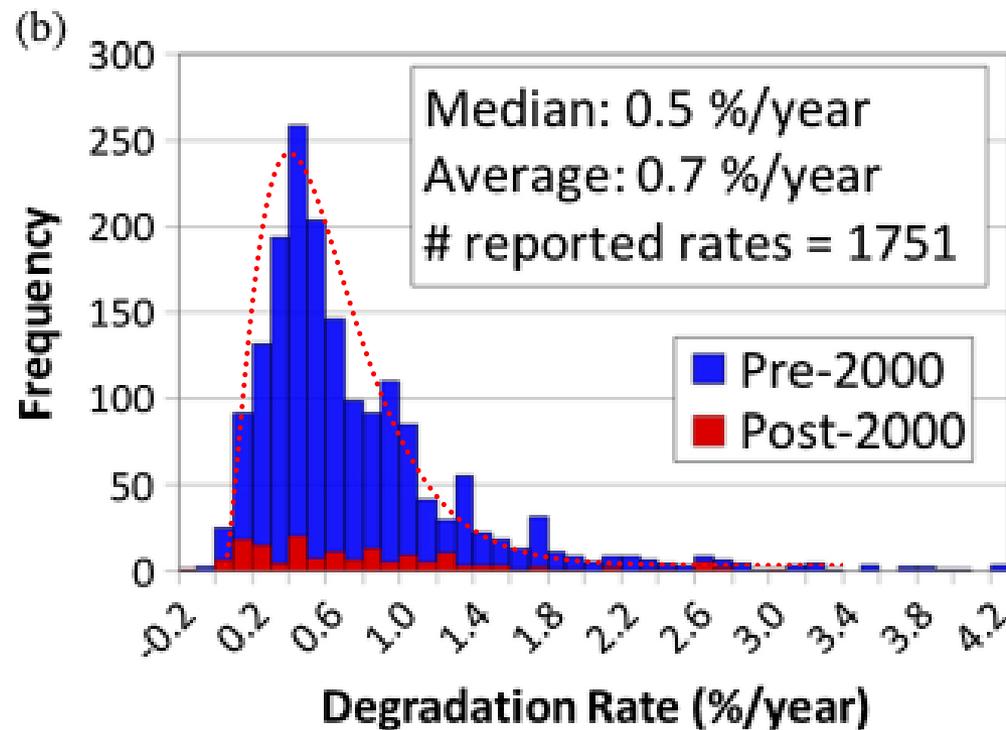


Extend to arbitrary, realistic module power distributions
Relate broadening to degradation rate distributions



Context: Jordan and Kurtz

- Encompassing compilation of published measured annual degradation rates r_D for PV modules
- Example result: Distribution $q(r_D)$ for crystalline Si modules



D.C. Jordan and
S.R. Kurtz,
Prog. Photovolt.:
Res. Appl. (2011).

Reasonably good fit with gamma distribution

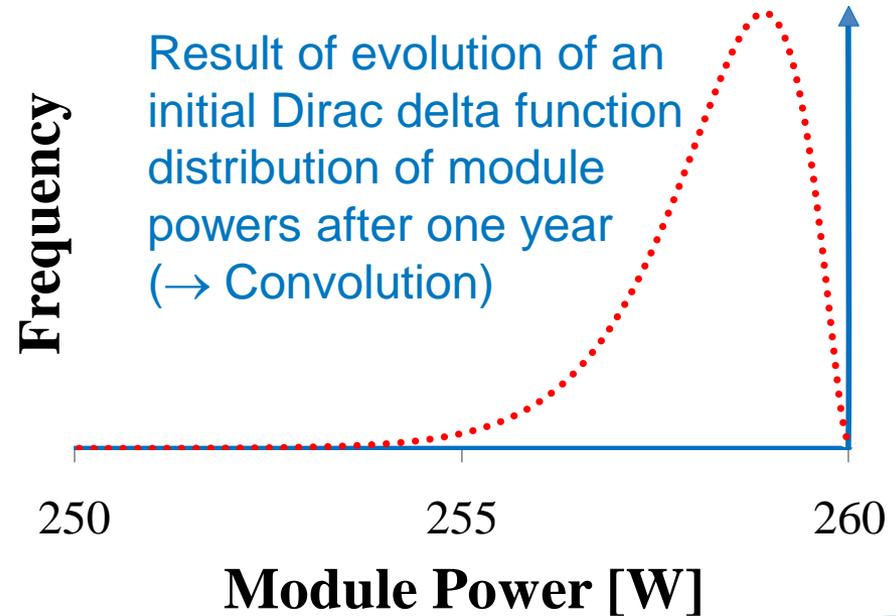
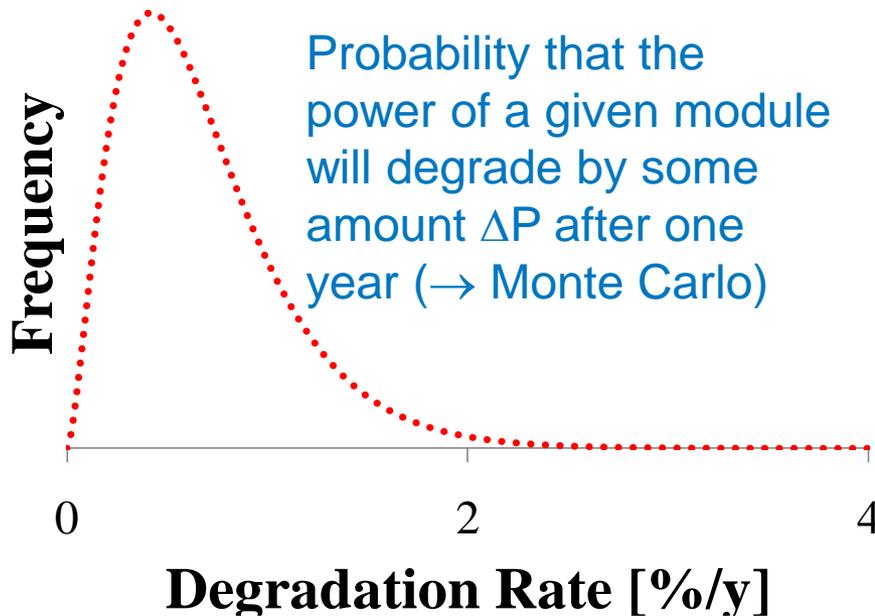


Annual Degradation Rate: A Fresh Look

- Determined from power P measured at time t and $t+\Delta t$

$$r_D = \frac{[P(t) - P(t + \Delta t)]}{\Delta t} \quad (\text{with } \Delta t \text{ in years})$$

- Repeating this for module population yields distribution $q(r_D)$
- Two interpretations of $q(r_D)$:



Systematic Approaches: Introduction

- Monte Carlo simulation (evolution from year n to year $n+1$ by sampling module power & degradation rate distributions):

$$p_{n+1}^s(P) = p_n^s(P) - \tilde{q}^s(\Delta P)$$

- Convolution approach [used, e.g., to solve heat or diffusion equation, kernel is “fundamental solution” for $\delta(P-P_0)$]:

$$p_{n+1}(P) = \int_{-\infty}^{+\infty} p_n(P') \tilde{q}[-(P - P')] dP'$$

Kernel

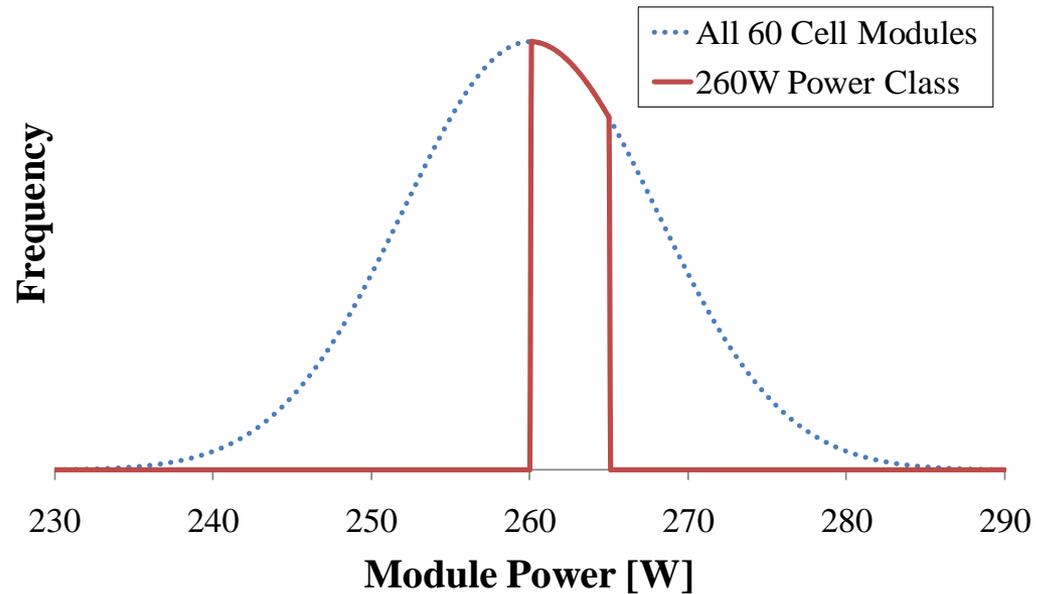
- Main new aspects:
 - ✓ Applicable to arbitrary initial module power distributions
 - ✓ Explicitly consider distributions of degradation rates $q(r_D)$



Systematic Approaches: Choice of Parameters

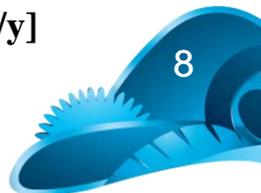
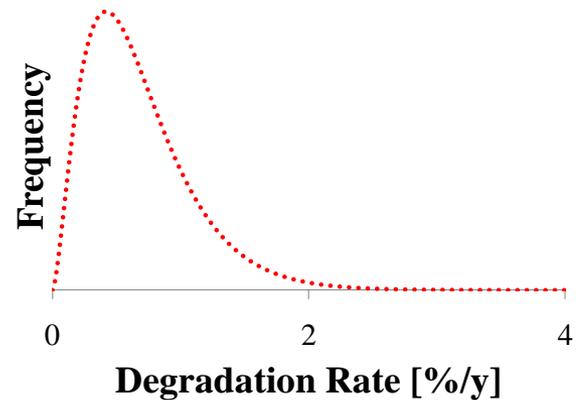
- Realistic initial module power distribution:

- ✓ Truncated Gaussian
- ✓ Representing one power class for given module construction



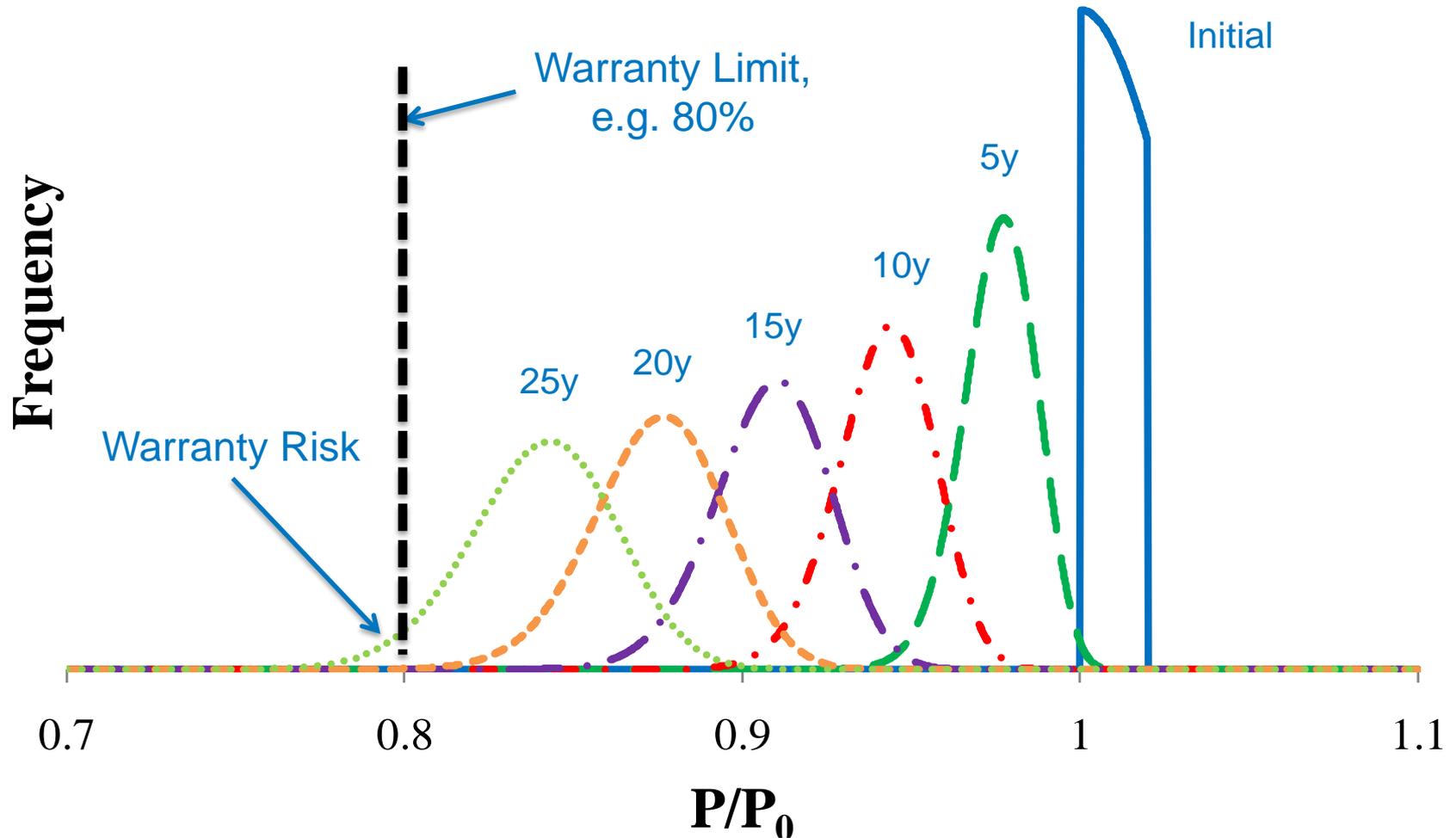
- Degradation rate distribution:

- ✓ Gamma distribution fit to data for mono c-Si by Jordan & Kurtz
- ✓ Maximum at 0.42%, median of 0.59%



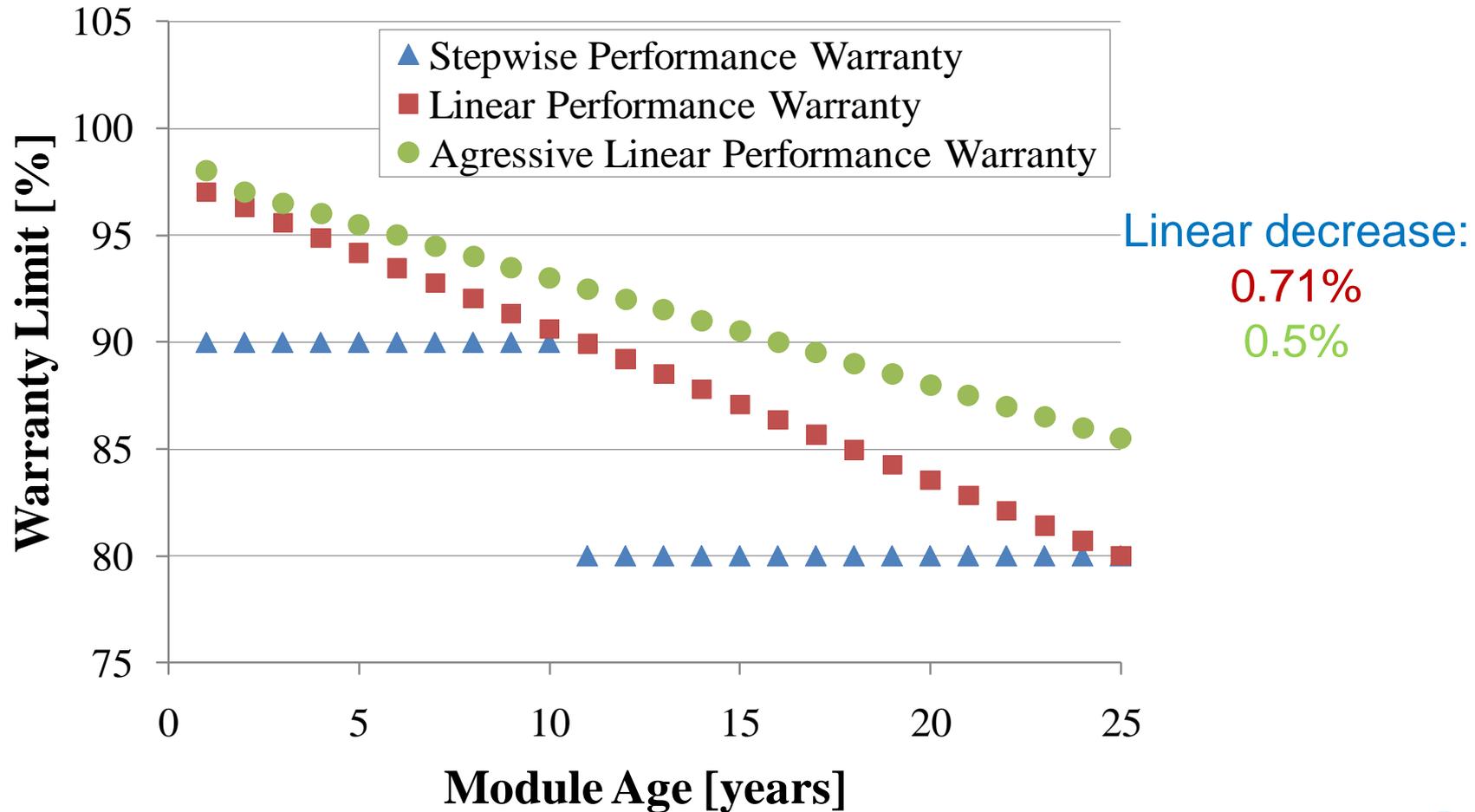
Systematic Approaches: Central Result

- Time evolution:



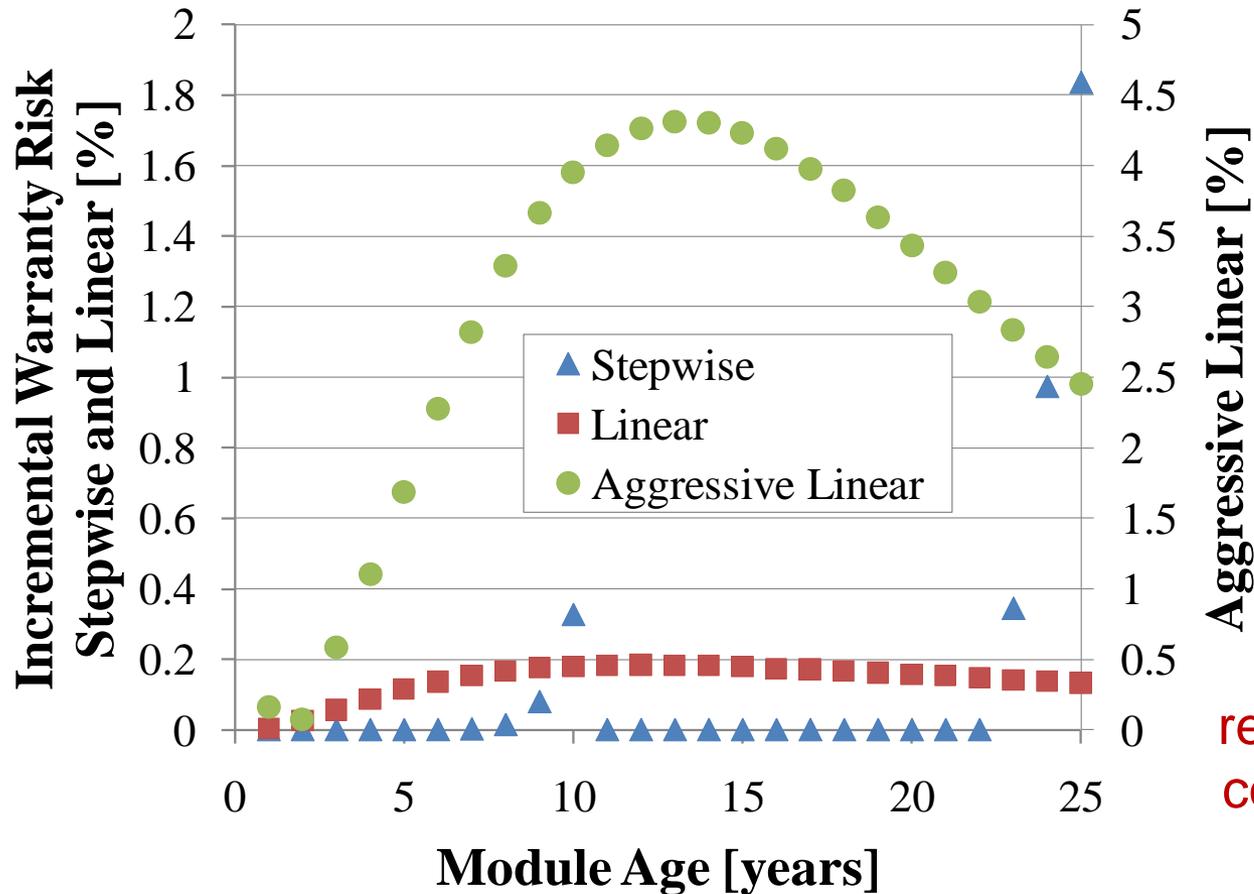
Application: Performance Warranties

- Three different examples:



Application: Incremental Warranty Risk

- “Incremental warranty risk” = percentage of modules underperforming for the first time at a given module age



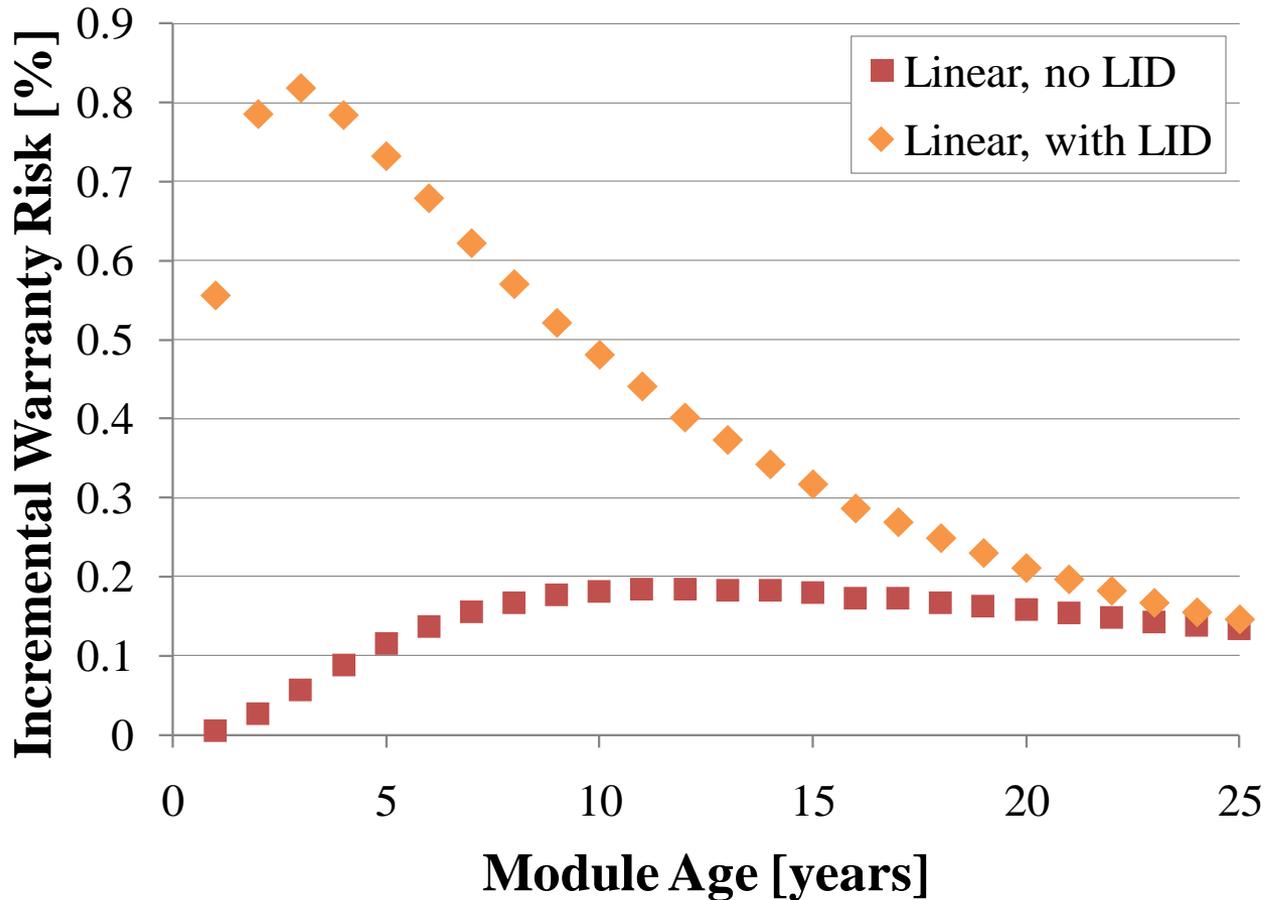
Total warranty risk:
3.6%
3.6%
74%!!!

Higher cost of replacement, tighter control over system performance



Application: Influence of Light-Induced Degradation

- LID: Gaussian with average 1.3%, std. deviation 0.24%



Total warranty risk:
3.6%
10%



Summary and Outlook

- Summary:
 - ✓ Two systematic and general approaches for time evolution of module power distributions presented
 - ✓ Simple application to comparison of incremental warranty risk for different warranty terms demonstrates basic utility
 - ✓ Effects of LID easily incorporated
- Outlook:
 - ✓ Use actual distributions for module power & degradation rates
 - ✓ Consider module volume from different production years
 - ✓ Consider time dependence of cost of module replacement
 - ✓ Time dependence of degradation rate distributions?



Thanks for your attention!

